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Figure 13. Decoupling Capacitance Hierarchy -

Figure 13. Decoupling Capacitance Hierarchy P.C. Board Power Supply L Proc. VLSI Signal Processing Workshop, IEEE Press, May 1994. [44]N. Seghal, C. Chen and

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Spyros Tragoudas, VLSI Design, Special issue on High Performance CAD for Proceedings of the 1993 IEEE International Conference on Computer

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Yehea Ismail - American University in Cairo -

and a guest editor for a special issue of the IEEE on Very Large Scale Integration Drop, Proceedings of ISCAS, pp. 481-484, May

VLSI reliability challenges: From device physics -

Japanese and American IC industries concerning VLSI reliability, Proceedings of the IEEE, Vol.81, No.5, May 1993. shift, reliability issues for

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